



Date: December 13, 2019

To,

NOVASYS GREENERGY PRIVATE LIMITED

Khasra No. 185, Mouza: Mahalgaon, Tahsil: Kamptee, Nagpur – 441202, Maharashtra, India.

Sub: PID Testing for One BOM (one cell family) of PV Modules as per customer specification and partially as per IEC TS 62804 (one Cycle) – two cell family

We hereby acknowledge receipt of samples of **Poly-Crystalline & Mono PERC Solar Photovoltaic Modules** with details of Bill of material for the samples of Model **NOVA335P72 & NOVA400MP72** submitted by **NOVASYS GREENERGY PRIVATE LIMITED**, for testing pursuant to the below mentioned IEC Standard partially for PID test with reference to Project No. 4789223052. After the successful completion of testing, all the samples met the pass criteria with the degradation of less than 5%. The final test report has been submitted to Novasys Greenergy with report no. 4789223052-S1, issue dated 13 December 2019.

Models covered:

NOVA400MP72, NOVA395MP72, NOVA390MP72, NOVA385MP72, NOVA380MP72,
NOVA375MP72, NOVA370MP72, NOVA365MP72, NOVA360MP72, NOVA355MP72,
NOVA350MP72, NOVA345MP72, NOVA340MP72

NOVA335P72, NOVA330P72, NOVA325P72, NOVA320P72, NOVA315P72,
NOVA310P72, NOVA305P72, NOVA300P72

Standard:

As per customer specification and partially as per IEC TS 62804-1 Edition 1.0 2015-08: Photovoltaic (PV) modules – Test methods for the detection of potential-induced degradation – Part 1: Crystalline silicon

Test Condition:

Test Duration:	1 Cycle of 96 hours
Temperature:	85±2°C
Humidity:	85±3%RH
Applied Potential:	1500V

Sincerely Yours,

Srimathy N

Engineer Project Associate

UL India Private Limited.

